

November 2013

### **FDMS015N04B**

# N-Channel PowerTrench<sup>®</sup> MOSFET 40 V, 100 A, 1.5 m $\Omega$

### **Features**

- $R_{DS(on)}$  = 1.13 m $\Omega$  (Typ.) @  $V_{GS}$  = 10 V,  $I_D$  = 50 A
- Advanced Package and Silicon Combination for Low R<sub>DS(on)</sub> and High Efficiency
- · Fast Switching Speed
- · 100% UIL Tested
- · RoHS Compliant

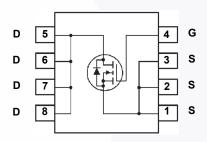
### Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advance PowerTrench® process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

### **Applications**

- · Synchronous Rectification for ATX / Server
- · Battery Protection Circuit
- · Motor Drives and Uninterruptible Power Supplies





### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol		FDMS015N04B	Unit		
$V_{DSS}$	Drain to Source Voltage	Drain to Source Voltage			V
$V_{GSS}$	Gate to Source Voltage			±20	V
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		100	۸
'D	Diam Current	- Continuous (T <sub>A</sub> = 25°C)	(Note 1a)	31.3	Α
I <sub>DM</sub>	Drain Current	Drain Current - Pulsed (Note 2)		400	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy	Single Pulsed Avalanche Energy (Note 3)		526	mJ
D	Power Dissipation	$(T_C = 25^{\circ}C)$		104	W
$P_{D}$	Power Dissipation	$(T_A = 25^{\circ}C)$	(Note 1a)	2.5	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C

### **Thermal Characteristics**

Symbol	Parameter	FDMS015N04B	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 1	a) 50	- C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS015N04B	FDMS015N04B	Power 56	13 "	12 mm	3000 units

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A},  V_{GS} = 0 \text{V}$	40	-	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C	-	37	-	mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 50 A	-	1.13	1.5	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 50 A	-	171	-	S

### **Dynamic Characteristics**

-						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V f = 1 MHz		6560	8725	pF
Coss	Output Capacitance			2795	3720	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			162	-	pF
C <sub>oss</sub> (er)	Energy Releted Output Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V	-	3896	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-\	91	118	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 50 A	-	26	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	V <sub>GS</sub> = 0 V to 10 V	-	9	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note	- 4)	16	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	1.4	-	Ω

### **Switching Characteristics**

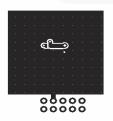
t <sub>d(on)</sub>	Turn-On Delay Time		-	34	78	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 20 \text{ V}, I_{D} = 50 \text{ A}$	-	24	58	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 4.7 \Omega$	-	71	152	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-/	26	62	ns

### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diod	Maximum Continuous Drain to Source Diode Forward Current			100	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	400	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 50 A		-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 50 A	-	78	<b>/</b>	ns
Q <sub>rr</sub>	Reverse Recovery Charge dI <sub>F</sub> /dt = 100 A/μs		-	90	-	nC

#### Notes

TAR<sub>9,A</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>9,JC</sub> is guaranteed by design while R<sub>9CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



 b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Repetitive rating: pulse-width limited by maximum junction temperature.

<sup>3.</sup> L = 3 mH,  $I_{AS}$  = 18.72 A, starting  $T_{J}$  = 25°C.

<sup>4.</sup> Essentially independent of operating temperature typical characteristics.

### **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

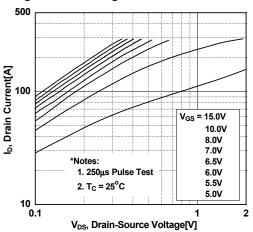


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

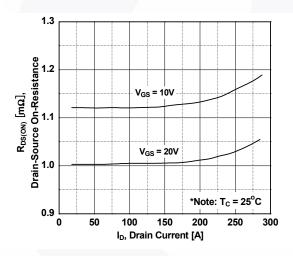


Figure 5. Capacitance Characteristics

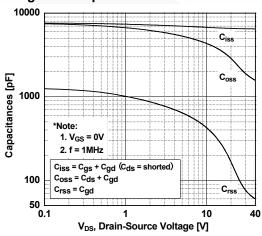


Figure 2. Transfer Characteristics

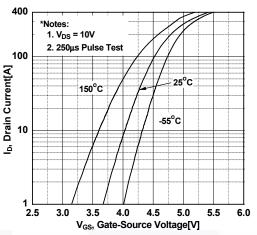


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

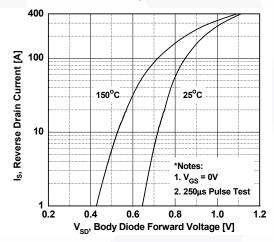
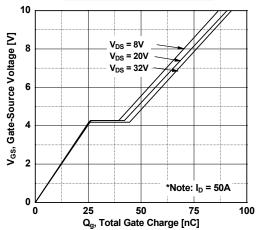


Figure 6. Gate Charge Characteristics



### **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

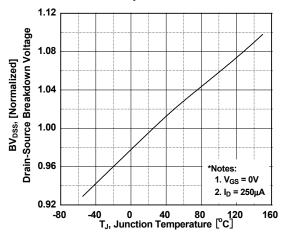


Figure 9. Maximum Safe Operating Area

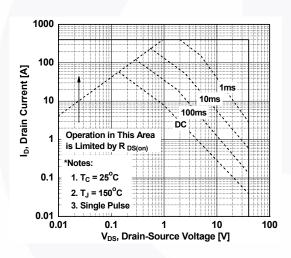


Figure 11. Eoss vs. Drain to Source Voltage

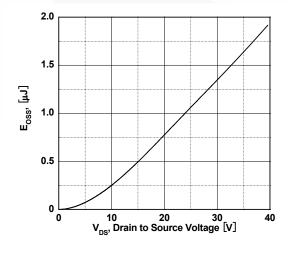


Figure 8. On-Resistance Variation vs. Temperature

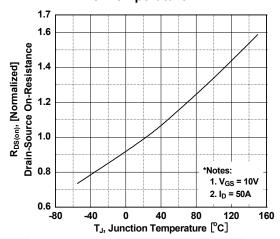


Figure 10. Maximum Drain Current vs. Case Temperature

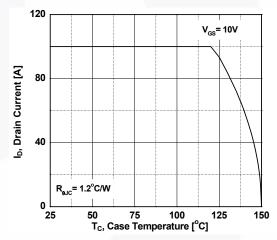
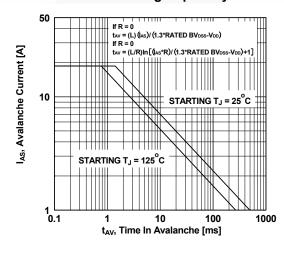
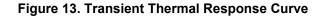


Figure 12. Unclamped Inductive Switching Capability



## **Typical Performance Characteristics** (Continued)



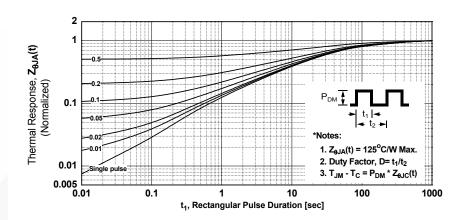


Figure 14. Gate Charge Test Circuit & Waveform

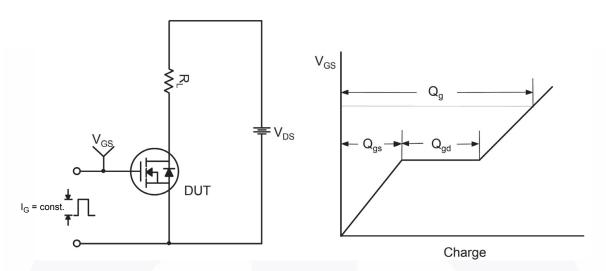


Figure 15. Resistive Switching Test Circuit & Waveforms

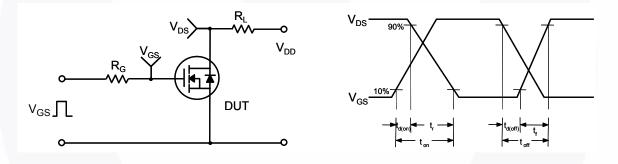
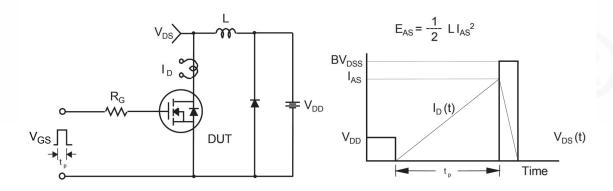


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms



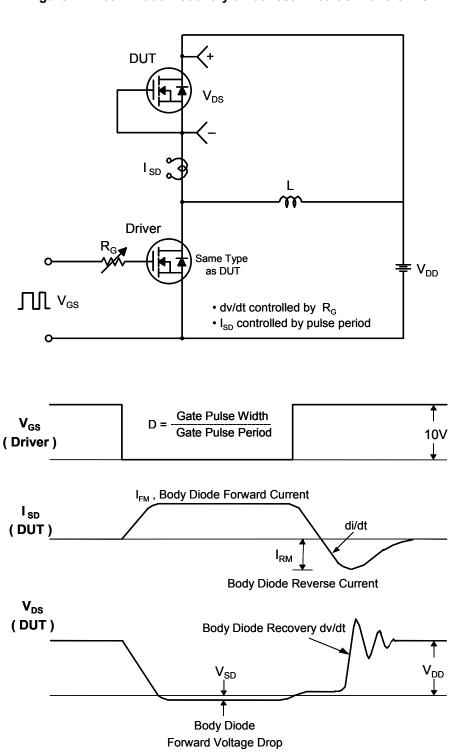
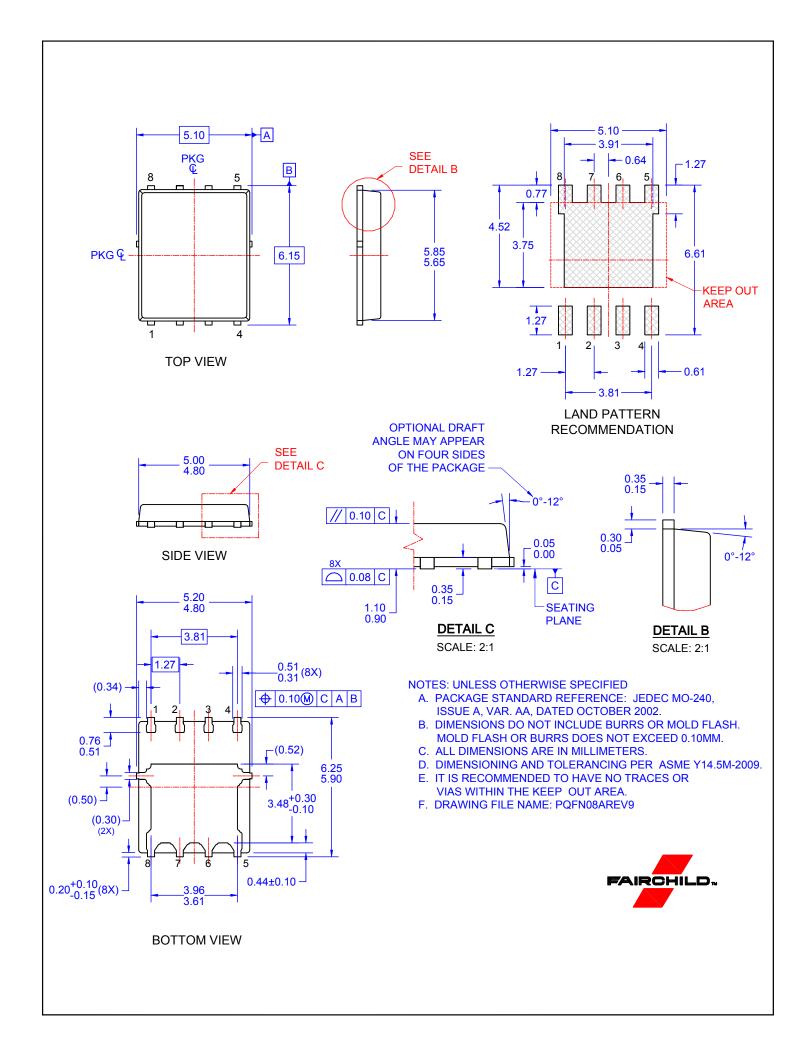


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms







#### TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

AccuPower™ F-PFS™ AttitudeEngine™ FRFET®

Global Power Resource<sup>SM</sup> Awinda<sup>®</sup> AX-CAP®\*

GreenBridge™ BitSiC™ Green FPS™ Build it Now™ Green FPS™ e-Series™

CorePLUS™ Gmax™ CorePOWER™  $\mathsf{GTO}^{\mathsf{TM}}$ CROSSVOLT™ IntelliMAX™ CTL™ ISOPLANAR™

Current Transfer Logic™ Making Small Speakers Sound Louder

**DEUXPEED®** and Better™ Dual Cool™ MegaBuck™ EcoSPARK® MIČROCOUPLER™ EfficientMax™

MicroFET™ **ESBC™** MicroPak™ **-**® MicroPak2™ MillerDrive™ Fairchild®

MotionMax™ Fairchild Semiconductor® MotionGrid® FACT Quiet Series™ MTi<sup>®</sup> FACT MTx® FAST<sup>®</sup> MVN® FastvCore™ mWSaver® FETBench™ OptoHiT™ FPS™ OPTOLOGIC® OPTOPLANAR®

Power Supply WebDesigner™ PowerTrench®

PowerXSTI

Programmable Active Droop™

OFFT QS™ Quiet Series™ RapidConfigure™

Saving our world, 1mW/W/kW at a time™

SignalWise™ SmartMax™ SMART START™

Solutions for Your Success™

SPM® STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™ Sync-Lock™

TinyBoost<sup>®</sup> TinyBuck<sup>®</sup> TinyCalc™ TinyLogic<sup>®</sup> TINYOPTO™ TinvPower™ TinyPWM™ TinyWire™ TranSiC™ TriFault Detect™ TRUECURRENT®\* uSerDes™

SYSTEM SYSTEM

UHC Ultra FRFET™ UniFET™ VCX™ VisualMax™ VoltagePlus™ XSTM. Xsens™

仙童™

\* Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. TO OBTAIN THE LATEST, MOST UP-TO-DATE DATASHEET AND PRODUCT INFORMATION, VISIT OUR <u>AIRCHILDSEMI.COM.</u> FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

Unless otherwise specified in this data sheet, this product is a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability. This product may not be used in the following applications, unless specifically approved in writing by a Fairchild officer: (1) automotive or other transportation, (2) military/aerospace, (3) any safety critical application - including life critical medical equipment - where the failure of the Fairchild product reasonably would be expected to result in personal injury, death or property damage. Customer's use of this product is subject to agreement of this Authorized Use policy. In the event of an unauthorized use of Fairchild's product, Fairchild accepts no liability in the event of product failure. In other respects, this product shall be subject to Fairchild's Worldwide Terms and Conditions of Sale, unless a separate agreement has been signed by both Parties.

#### **ANTI-COUNTERFEITING POLICY**

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com,

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufacturers of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed applications, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address any warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Deminition of Terms		
Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev 175

# **Mouser Electronics**

**Authorized Distributor** 

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

FDMS015N04B